

Abstract

The invention relates to a device for checking or calibrating the angle-dependent alignment of a reference structure on a high-precision test-piece. The device comprises a plinth, a retainer piece, mounted such as to rotate about a retainer piece axis, for retaining the test-piece and a measuring piece with a measuring piece bearing unit, for the rotational mounting of the measuring piece, about a measuring piece axis. An optical unit is mounted on the measuring piece, for receiving at least one test-piece beam, interacting with the reference structure on the test piece, running essentially in a measuring plane. The measuring piece bearing unit is arranged to one side of the measuring plane or on the measuring plane. The measuring piece includes a base form which is for a large part axially symmetrical with the measuring piece axis and encompasses or surrounds the intersection of the measuring piece axis with the retainer piece axis on the measuring plane and hence also encompasses or surrounds the test-piece.